



**International Scientific Instruments, Inc.
announces
a new high performance
table-top
scanning electron microscope**



The Super Mini-SEM[®] II

During the past three years, International Scientific Instruments has pioneered the concept of the precision table-top scanning electron microscope . . . a concept which offers the scientific community excellent performance at reasonable prices. Among the "MINI-SEM" instruments which have gained world-wide acceptance is the popular Super Mini-SEM. It became an overnight success when it was introduced a year ago because it offered versatility, reliability and high performance along with simple operation and table-top convenience. As a result of this successful experience with the Super Mini-SEM, and a

continuing development program, International Scientific Instruments is now able to offer along with the Super Mini-SEM, the Super Mini-SEM II.

These two scanning electron microscopes provide a choice of instrumentation that will closely satisfy both application and budget requirements.

Super Mini-SEM II was specifically designed for those researchers who require that extra amount of resolution, 70 Angstroms, separate CRT's, large specimen stage, and other useful features. It is the finest instrument ever offered by ISI.

OUTSTANDING FEATURES

SUPER MINI-SEM I SUPER MINI-SEM II

Resolution

100 Angstroms guaranteed

Accelerating Voltage

Variable—
2-10-25KV, 2-15-25KV,
10-15-25KV.

Magnification Range

30X to 160,000X
direct reading compensated
for working distance

Standard Operating Modes

Secondary electron
Backscattered electron
External
Line—with Y control } for X-Ray
Spot—with X control } analysis

X-Ray Analysis

easily interfaced to most
Energy Dispersive X-Ray systems

Cathode Ray Tube

Separate viewing and
recording CRT
Option—May be ordered with one CRT
for viewing and recording. Second CRT
may be added on order.

Vacuum System

Manual operation

TV Scan

Available as an option

Dynamic Focusing

Automatically compensates for
defocusing at low magnification and
high tilt angles.

Stages

Model T-X-Y stage standard

-30° to 60° tilt,
X-Y motion ± 7.5 mm
Other optional stages include
tilting and rotating stage,
Large Universal Z stage,
Model U-TXRYZ

Resolution

70 Angstroms guaranteed

Accelerating Voltage

Variable—three options
10-15-25KV, 2-10-25KV or 2, 15, 25KV.

Magnification Range

30X to 160,000X
direct reading compensated
for working distance

Standard Operating Modes

Secondary electron
Backscattered electron
External
Line—with Y control } for X-Ray
Spot—with X control } analysis

X-Ray Analysis

easily interfaced to most
Energy Dispersive X-Ray systems

Cathode Ray Tube

Separate viewing and
recording CRT (Standard)

Vacuum System

Automatic push button operation

TV Scan

Built in as standard

Dynamic Focusing

Automatically compensates for
defocusing at low magnification and
high tilt angles.

Stages

Large Universal Z stage,
Model U-TXRYZ standard
Tilt - 10° to + 70°
0 - 360° rotation,
X-Y motion ± 20 mm.
Z motion externally variable 8 - 38 mm.
Stage hinged to specimen chamber
for simple access.

For other specifications on both Super Mini Sems, refer to general brochure "Presenting Super Mini Sem."

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